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SHEET 1 OF 1

Form PTO 1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO.		SERIAL NO. 10/674,354							
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LIST OF	0555	RENCES CITED BY AP	DITCANT									
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				FILING DATE		GROUP						
				October 1, 2003		1731						
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JL	AA	4,891,055	01/02/1990	K. SHIBAOKA, et al.								
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		DOCUMENT NUMBER	DATE	COUNTRY		YES	FRANSLATION NO					
JL	AO	61-227932	10/11/1986	JAPAN (with English Abstract)			×					
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)												
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Examiner	A	/Jason La	zorcik/		Date Considered 10/06/2006							
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant												

Form PTO 1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. 243412US3	SERIAL NO. NEW APPLICATION						
				APPLICANT NEW AFFEIGATION				711014		
LIST OF REFERENCES CITED BY APPLICANT				Nobuhiro INOUE, et al.						
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		DOCUMENT	DATE	COUNTRY	TRANSLATION					
		NUMBER		COUNTRY		YES NO				
JL	AO	2000-351639	12/19/00	Japan (with English Abstract)				×		
	AP	WO98/22402	05/28/98	WIPO (with English Abstract)				×		
	AQ	1-122931	05/16/89	Japan (with English Abstract)		<u> </u>		X		
	AR	1-242428	09/27/89	Japan (with English Abstract)				X		
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	AZ				Additional References sheet(s) attached					
Examiner /Jason Lazorcik/					Date Cor	Date Considered 10/06/200				
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.										
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